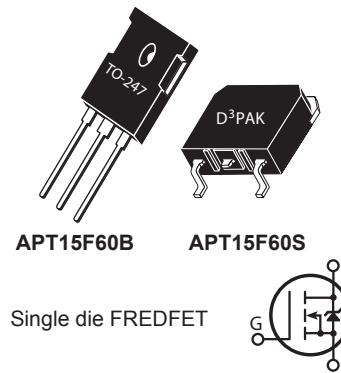


## N-Channel FREDFET

POWER MOS 8® is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t<sub>rr</sub>, soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C<sub>rss</sub>/C<sub>iss</sub> result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



### FEATURES

- Fast switching with low EMI
- Low t<sub>rr</sub> for high reliability
- Ultra low C<sub>rss</sub> for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant 

### TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

### Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I <sub>D</sub>	Continuous Drain Current @ T <sub>C</sub> = 25°C	16	A
	Continuous Drain Current @ T <sub>C</sub> = 100°C	10	
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	54	
V <sub>GS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>②</sup>	405	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	7	A

### Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Typ	Max	Unit
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25°C			290	W
R <sub>θJC</sub>	Junction to Case Thermal Resistance			0.43	°C/W
R <sub>θCS</sub>	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55		150	°C
T <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			300	
W <sub>T</sub>	Package Weight		0.22		oz
			6.2		g
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in·lbf
				1.1	N·m

## Static Characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified

APT15F60B\_S

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{BR(DSS)}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	600			V
$\Delta V_{BR(DSS)}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}, I_D = 250\mu\text{A}$		0.57		$\text{V}/^\circ\text{C}$
$R_{DS(on)}$	Drain-Source On Resistance <sup>③</sup>	$V_{GS} = 10V, I_D = 7\text{A}$		0.34	0.43	$\Omega$
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = .5\text{mA}$	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold Voltage Temperature Coefficient			-10		$\text{mV}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_J = 25^\circ\text{C}$			250	$\mu\text{A}$
		$V_{GS} = 0V, T_J = 125^\circ\text{C}$			1000	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 30V$			$\pm 100$	nA

## Dynamic Characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$g_{fs}$	Forward Transconductance	$V_{DS} = 50V, I_D = 7\text{A}$		14		S
$C_{iss}$	Input Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ $f = 1\text{MHz}$		2882		pF
$C_{rss}$	Reverse Transfer Capacitance			29		
$C_{oss}$	Output Capacitance			264		
$C_{o(cr)}^{\text{④}}$	Effective Output Capacitance, Charge Related	$V_{GS} = 0V, V_{DS} = 0V$ to $400V$		141		pF
$C_{o(er)}^{\text{⑤}}$	Effective Output Capacitance, Energy Related			73		
$Q_g$	Total Gate Charge	$V_{GS} = 0$ to $10V, I_D = 7\text{A},$ $V_{DS} = 300V$		72		nC
$Q_{gs}$	Gate-Source Charge			15		
$Q_{gd}$	Gate-Drain Charge			30		
$t_{d(on)}$	Turn-On Delay Time	<b>Resistive Switching</b> $V_{DD} = 400V, I_D = 7\text{A}$ $R_G = 10\Omega^{\text{⑥}}, V_{GG} = 15V$		16		ns
$t_r$	Current Rise Time			19		
$t_{d(off)}$	Turn-Off Delay Time			49		
$t_f$	Current Fall Time			15		

## Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$I_s$	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode)			15	A
$I_{SM}$	Pulsed Source Current (Body Diode) <sup>①</sup>				54	
$V_{SD}$	Diode Forward Voltage	$I_{SD} = 7A, T_J = 25^\circ\text{C}, V_{GS} = 0V$			1.0	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 7A^{\text{②}}$ $di_{SD}/dt = 100\text{A}/\mu\text{s}$ $V_{DD} = 100V$	$T_J = 25^\circ\text{C}$	167	190	ns
$Q_{rr}$	Reverse Recovery Charge		$T_J = 125^\circ\text{C}$	295	354	
$I_{rrm}$	Reverse Recovery Current		$T_J = 25^\circ\text{C}$	0.59		$\mu\text{C}$
$I_{rrm}$	Reverse Recovery Current		$T_J = 125^\circ\text{C}$	1.40		
$dv/dt$	Peak Recovery dv/dt		$T_J = 25^\circ\text{C}$	6.2		A
$dv/dt$	Peak Recovery dv/dt		$T_J = 125^\circ\text{C}$	8.5		

<sup>①</sup> Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

<sup>②</sup> Starting at  $T_J = 25^\circ\text{C}, L = 16.4\text{mH}, R_G = 25\Omega, I_{AS} = 7\text{A}$ .

<sup>③</sup> Pulse test: Pulse Width < 380 $\mu\text{s}$ , duty cycle < 2%.

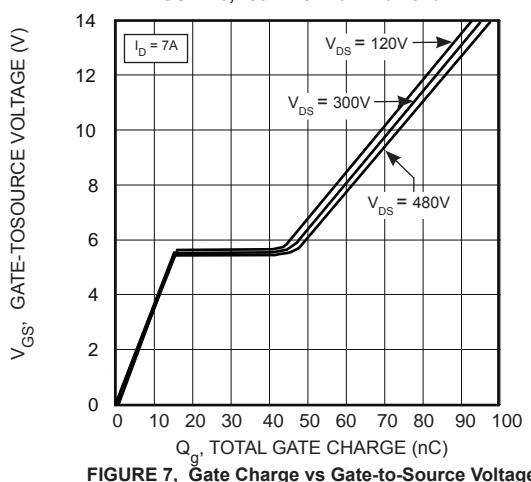
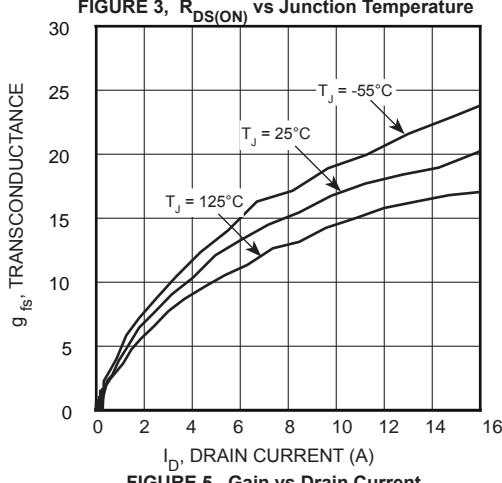
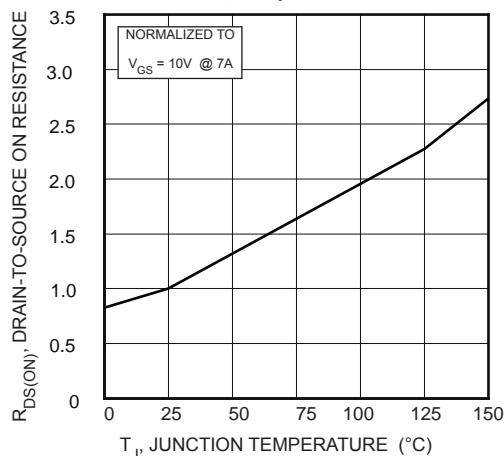
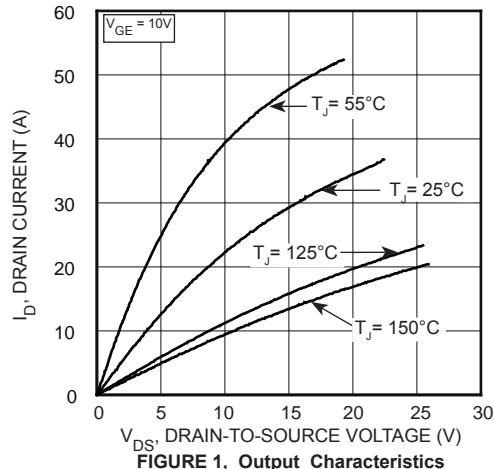
<sup>④</sup>  $C_{o(cr)}$  is defined as a fixed capacitance with the same stored charge as  $C_{oss}$  with  $V_{DS} = 67\%$  of  $V_{(BR)DSS}$ .

<sup>⑤</sup>  $C_{o(er)}$  is defined as a fixed capacitance with the same stored energy as  $C_{oss}$  with  $V_{DS} = 67\%$  of  $V_{(BR)DSS}$ . To calculate  $C_{o(er)}$  for any value of  $V_{DS}$  less than  $V_{(BR)DSS}$ , use this equation:  $C_{o(er)} = -3.43E-8/V_{DS}^2 + 1.44E-8/V_{DS} + 5.38E-11$ .

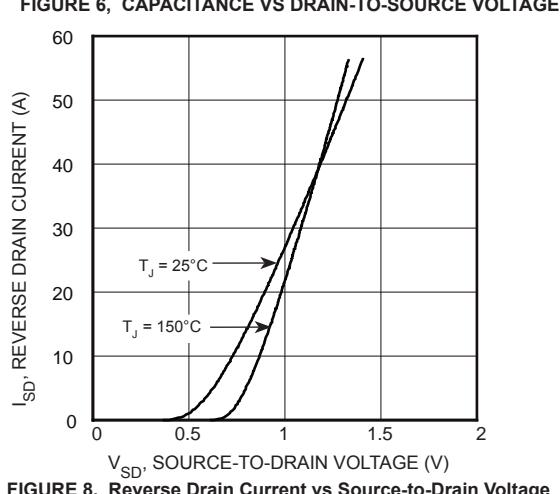
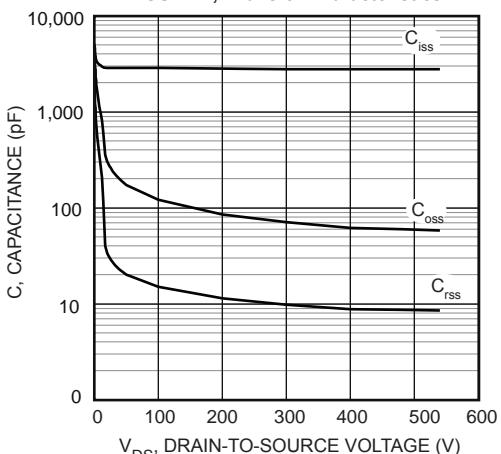
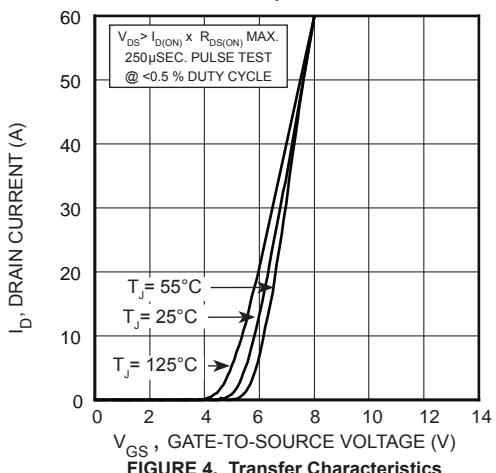
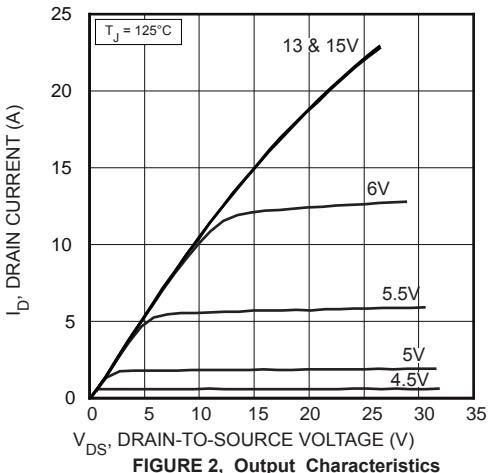
<sup>⑥</sup>  $R_G$  is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

## Typical Performance Curves



## APT15F60B\_S



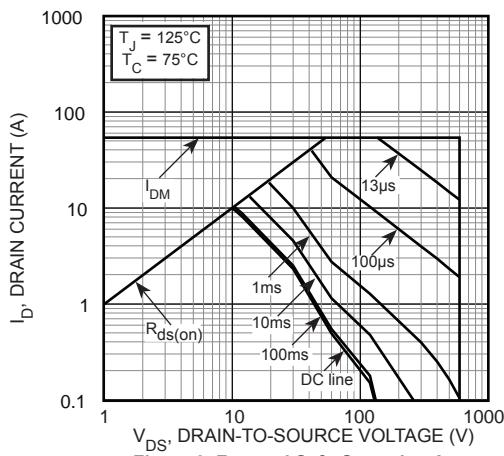


Figure 9, Forward Safe Operating Area

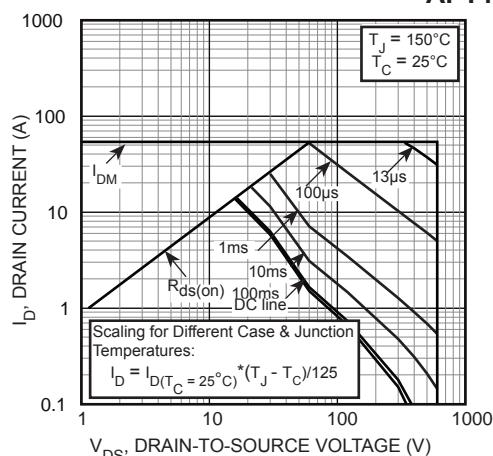


Figure 10, Maximum Forward Safe Operating Area

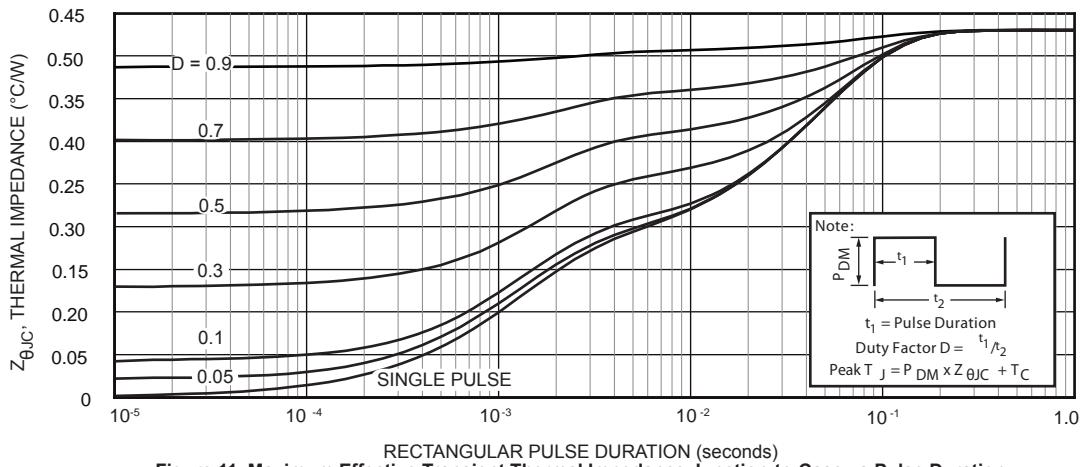
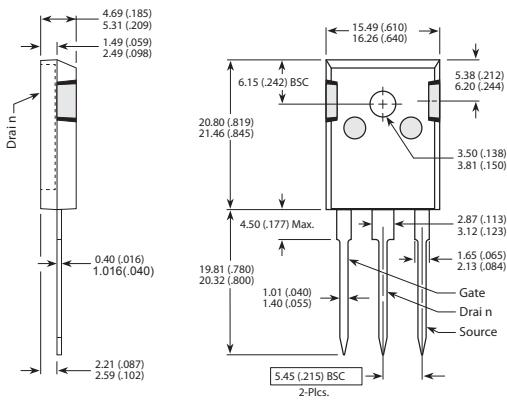


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

**TO-247 (B) Package Outline**

(e1) SAC: Tin, Silver, Copper

**D<sup>3</sup>PAK Package Outline**

(e3) 100% Sn Plated

